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SNOS047B - MAY 2004 - REVISED SEPTEMBER 2011

54ABT543 Octal Registered Transceiver with TRI-STATE® Outputs

Check for Samples: 54ABT543

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direction

Guaranteed latchup protection

High impedance glitch free bus loading during

Standard Military Drawing (SMD) 5962-9231401

entire power up and power down cycle

Nondestructive hot insertion capability

FEATURES

- Back-to-back registers for storage ٠
- **Bidirectional data path**
- A and B outputs have current sourcing . capability of 24 mA and current sinking capability of 48 mA
- Separate controls for data flow in each

DESCRIPTION

The 'ABT543 octal transceiver contains two sets of D-type latches for temporary storage of data flowing in either direction. Separate Latch Enable and Output Enable inputs are provided for each register to permit independent control of inputting and outputting in either direction of data flow.

Connection Diagram



19 20 21 22 23 24 25 B6 B5 B4 NC B3 B2 B1

26 B₀

Figure 1. Pin Assignment for

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~7 12
CEAB 13
GND 14
NC 15
OEAB 16
LEAB 17
B7 18

B₇ 18

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Pin Functions

Pin Descriptions					
Pin Names Description					
OEAB, OEBA	Output Enable Inputs				
LEAB , LEBA	Latch Enable Inputs				
CEAB, CEBA	Chip Enable Inputs				
A ₀ -A ₇	Side A Inputs or TRI-STATE Outputs				
B ₀ -B ₇	Side B Inputs or TRI-STATE Outputs				

Functional Description

The 'ABT543 contains two sets of D-type latches, with separate input and output controls for each. For data flow from A to B, for example, the A to B Enable (CEAB) input must be low in order to enter data from the A port or take data from the B port as indicated in the Data I/O Control Table. With CEAB low, a low signal on (LEAB) input makes the A to B latches transparent; a subsequent low to high transition of the LEAB line puts the A latches in the storage mode and their outputs no longer change with the A inputs. With CEAB and OEAB both low, the B output buffers are active and reflect the data present on the output of the A latches. Control of data flow from B to A is similar, but using the CEBA, LEBA and OEBA.

Table 1. Data I/O Control Table

	Inputs		Latch Status	Output Buffors	
CEAB	LEAB	OEAB	Laten Status	Output Buffers	
Н	Х	Х	Latched	High Z	
Х	Н	Х	Latched	—	
L	L	Х	Transparent	—	
Х	Х	Н	_	High Z	
L	Х	L	—	Driving	





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These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

Absolute Maximum Ratings ⁽¹⁾

Storage Temperature	−65°C to +150°C
Ambient Temperature under Bias	-55°C to +125°C
Junction Temperature under Bias	
Ceramic	−55°C to +175°C
V _{CC} Pin Potential to	
Ground Pin	-0.5V to +7.0V
Input Voltage (2)	-0.5V to +7.0V
Input Current ⁽²⁾	-30 mA to +5.0 mA
Voltage Applied to Any Output	
in the Disable or Power-Off State	-0.5V to +5.5V
in the HIGH State	–0.5V to V_{CC}
Current Applied to Output	
in LOW State (Max)	twice the rated I _{OL} (mA)
DC Latchup Source Current	-500 mA
Over Voltage Latchup (I/O)	10V

(1) Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

(2) Either voltage limit or current limit is sufficient to protect inputs.

Recommended OperatingConditions

Free Air Ambient Temperature	
Military	−55°C to +125°C
Supply Voltage	
Military	+4.5V to +5.5V
Minimum Input Edge Rate	$(\Delta V/\Delta t)$
Data Input	50 mV/ns
Enable Input	20 mV/ns
Clock Input	100 mV/ns

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STRUMENTS

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DC Electrical Characteristics

	_	Parameter		ABT54	3	11		Conditions
Symbol	Parame	eter	Min Typ Max Units		V _{cc}	Conditions		
V _{IH}	Input HIGH Voltage		2.0			V		Recognized HIGH Signal
V _{IL}	Input LOW Voltage				0.8	V		Recognized LOW Signal
V _{CD}	Input Clamp Diode Volta	ige			-1.2	V	Min	I _{IN} = −18 mA (Non I/O Pins)
V _{OH}	Output HIGH Voltage	54ABT	2.5					$I_{OH} = -3 \text{ mA}, (A_n, B_n)$
		54ABT	2.0			V	Min	$I_{OH} = -24 \text{ mA}, (A_n, B_n)$
V _{OL}	Output LOW Voltage	54ABT			0.55	V	Min	$I_{OL} = 48 \text{ mA}, (A_n, B_n)$
V _{ID}	Input Leakage Test		4.75			V	0.0	I _{ID} = 1.9 μA, (Non-I/O Pins)
								All Other Pins Grounded
I _{IH}	Input HIGH Current				5	μA	Max	V_{IN} = 2.7V (Non-I/O Pins) ⁽¹⁾
								V _{IN} = V _{CC} (Non-I/O Pins)
I _{BVI}	Input HIGH Current Brea	akdown Test			7	μA	Max	V _{IN} = 7.0V (Non-I/O Pins)
BVIT	Input HIGH Current				100	μA	Max	V _{IN} = 5.5V (A _n , B _n)
	Breakdown Test (I/O)							
IIL	Input LOW Current				-5	μA	Max	V _{IN} = 0.5V (Non-I/O Pins) ⁽¹⁾
								V _{IN} = 0.0V (Non-I/O Pins)
I _{IH} + I _{OZH}	Output Leakage Current				50	μA	0V-5.5V	V _{OUT} = 2.7V (A _n , B _n);
								\overline{OEAB} or $\overline{CEAB} = 2V$
I _{IL} + I _{OZL}	Output Leakage Current				-50	μA	0V-5.5V	V _{OUT} = 0.5V (A _n , B _n);
								\overline{OEAB} or $\overline{CEAB} = 2V$
l _{os}	Output Short-Circuit Cur	rent	-100		-275	mA	Max	$V_{OUT} = 0V (A_n, B_n)$
ICEX	Output HIGH Leakage C	Current			50	μA	Max	$V_{OUT} = V_{CC} (A_n, B_n)$
ZZ	Bus Drainage Test				100	μA	0.0V	V _{OUT} = 5.5V (A _n , B _n);
								All Others GND
ICCLH	Power Supply Current				50	μA	Max	All Outputs HIGH
	Power Supply Current				30	mA	Max	All Outputs LOW
I _{CCZ}	Power Supply Current				50	μA	Max	Outputs TRI-STATE
								All Others at V _{CC} or GND
Сст	Additional I _{CC} /Input				2.5	mA	Max	$V_{I} = V_{CC} - 2.1V$
								All Others at V _{CC} or GND
I _{CCD}	Dynamic I _{CC}	No Load						Outputs Open, CEAB
	(1)				0.18	mA/MHz	Max	and $\overline{OEAB} = GND, \overline{CEBA} = V_0$ One Bit Toggling,
								50% Duty Cycle, (2)

(1) Guaranteed but not tested. (2) For 8-bit toggling. $I_{CCD} < 1.4$ mA/MHz.

DC Electrical Characteristics

						Conditions
Symbol	Parameter	Min	Max	Units	V _{cc}	C _L = 50 pF,
						$R_L = 500\Omega$
V _{OLP}	Quiet Output Maximum Dynamic V _{OL}		1.1	V	5.0	$T_A = 25^{\circ}C^{(1)}$
V _{OLV}	Quiet Output Minimum Dynamic V _{OL}		-0.45	V	5.0	$T_A = 25^{\circ}C^{(1)}$

(1) Max number of outputs defined as (n). n - 1 data inputs are driven 0V to 3V. One output at LOW.



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AC Electrical Characteristics

		54A	BT		
		T _A = −55°C		Fig.	
Symbol	Parameter	V _{CC} = 4.5V–5.5V		Units	No.
		C _L = 5	50 pF		
		Min	Max		
t _{PLH}	Propagation Delay	1.6	6.4	ns	Figure 4
t _{PHL}	A_n to B_n or B_n to A_n	1.6	6.2		
t _{PLH}	Propagation Delay				
t _{PHL}	$\overline{\text{LEAB}}$ to B _n , $\overline{\text{LEBA}}$ to A _n	1.6	6.6	ns	Figure 4
	\overline{OEBA} or \overline{OEAB} to A_n or B_n	1.6	6.4		
t _{PZH}	Enable Time				
t _{PZL}	LEAB to B _n , LEBA to A _n	1.3	6.4	ns	Figure 6
	\overline{OEBA} or \overline{OEAB} to A_n or B_n	1.8	7.4		
t _{PHZ}	Disable Time	2.0	7.2	ns	Figure 6
t _{PLZ}	\overline{CEBA} or \overline{CEAB} to A_n or B_n	1.5	7.0		

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AC Operating Requirements

		54/	ABT		
		T _A = −55°C		Fig.	
Symbol	Parameter	V _{CC} = 4	.5V–5.5V	Units	No.
		C _L =	50 pF		
		Min	Max		
t _S (H)	Setup Time, HIGH or LOW	3.5		ns	Figure 7
t _S (L)	A _n or B _n to LEBA or LEAB	3.0			
t _H (H)	Hold Time, HIGH or LOW	2.0		ns	Figure 7
t _H (L)	A _n or B _n to LEBA or LEAB	2.0			
t _S (H)	Setup Time, HIGH or LOW	3.3		ns	Figure 7
t _S (L)	A_n or B_n to \overline{CEAB} or \overline{CEBA}	2.5			
t _H (H)	Hold Time, HIGH or LOW	2.0		ns	Figure 7
t _H (L)	A_n or B_n to \overline{CEAB} or \overline{CEBA}	2.0			
t _W (L)	Pulse Width, LOW	3.5		ns	Figure 5

Capacitance

Symbol	Parameter	Тур	Units	Conditions: T _A = 25°C
C _{IN}	Input Capacitance	5.0	pF	V _{CC} = 0V (non I/O pins)
C _{I/O} ⁽¹⁾	Output Capacitance	11.0	pF	$V_{CC} = 5.0V (A_n, B_n)$

(1) $C_{I/O}$ is measured at frequency, f = 1 MHz, PER MIL-STD-883, METHOD 3012.

AC Loading





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Test Input Signal Requirements

Amplitude	Rep. Rate	t _w	t _r	t _f
3V	1 MHz	500 ns	2.5 ns	2.5 ns





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